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# jmr Journal of MATERIALS RESEARCH

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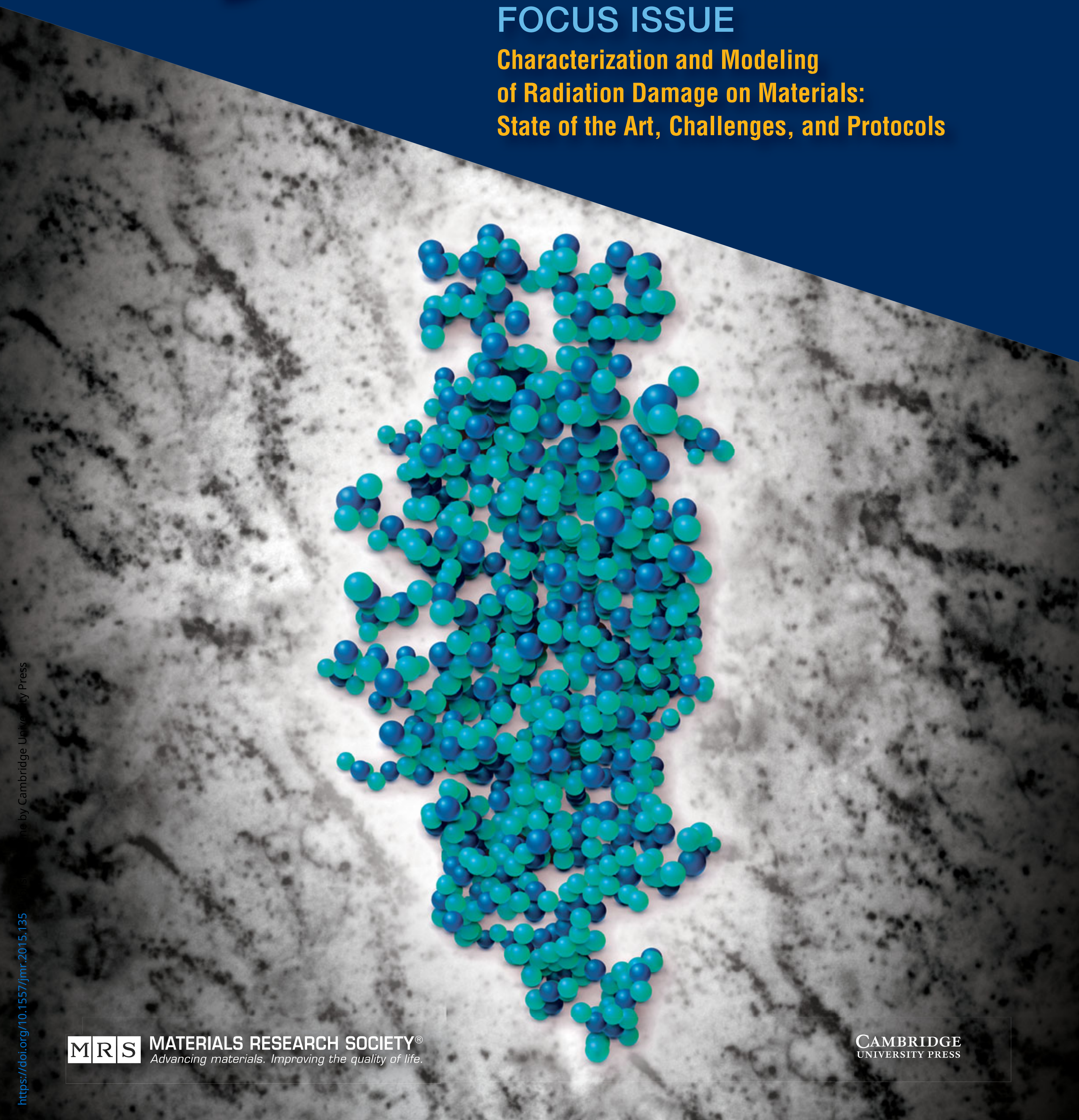
## FOCUS ISSUE

## Characterization and Modeling of Radiation Damage on Materials: State of the Art, Challenges, and Protocols



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